



MULTILAYER CERAMIC CAPACITORS

Low Profile Series

0402 to 1210 Sizes

X7R & X5R Dielectrics

Halogen Free & RoHS Compliance



*Contents in this sheet are subject to change without prior notice.

ASC_ Low Profile_(TT)

Dec. 2022



1. DESCRIPTION

MLCC consists of a conducting material and electrodes. To manufacture a chip-type SMT and achieve miniaturization, high density and high efficiency, ceramic condensers are used.

WTC TT series MLCC is used in product having thickness concerned generally have high capacitance and thinner product thickness. The high dielectric constant material X7R and X5R are used for this series product.

2. FEATURES

- a. Standard size with thin thickness.
- b. Small size with high capacitance.
- c. Capacitor with lead-free termination (pure Tin).

3. APPLICATIONS

- a. For LCD panels.
- b. For PCMCA cards.
- c. For IC packaging and modules.
- d. Any thickness concerned products.

4. HOW TO ORDER

Ξ	<u>15</u>	<u>×</u>	<u>475</u>	M	<u>6R3</u>	<u>C</u>	I
<u>Series</u>	<u>Size</u>	Dielectric	Capacitance	Tolerance	Rated voltage	Termination	Packaging
TT I ann maefila	AE 0400 (4005)		T. HE FILL	K JADOV	Turstingitiesent	C 0/NI:/Ca	T 7" no olo d
TT=Low profile	15 =0402 (1005)	1	Two significant	K =±10%	Two significant	C =Cu/Ni/Sn	T=7" reeled
	18 =0603 (1608)	X=X5R	digits followed by	M=±20%	digits followed by		G=13" reeled
	21 =0805 (2012)	+H	no. of zeros. And		no. of zeros. And		
	31 =1206 (3216)	1	R is in place of		R is in place of		
	32 =1210 (3225)		decimal point.		decimal point.		
				ÞA			
		8	eg.: PASSIVE SYS	TEM ALLIANCE	6R3=6.3 VDC		
		P	475=47x10 ⁵		100=10 VDC		
		120	=4,700,000pF		160=16 VDC		
		32	=4.7µF		250=25 VDC		
		C	Ala Col	9700	500=50 VDC		
			is cono	OgV VgO	101=100 VDC		

5. EXTERNAL DIMENSIONS

Size Inch (mm)	L (mm)	W (mm)	T (mm)/Symbol		M _B (mm)
0402 (1005)	1.00±0.2	0.5±0.2	0.30±0.03	L	0.25±0.10
0603 (1608)	1.6+0.15/-0.10	0.8+0.15/-0.10	0.50±0.10	Н	0.40±0.15
0805 (2012)	2.00±0.20	1.25±0.20	0.85±0.10	т	0.50±0.20
1006 (0016)	2 20 . 0 20	1 60 . 0 20	0.85±0.10	Т	0.60.0.20
1206 (3216)	3.20±0.20	1.60±0.20	1.15±0.15	J	0.60±0.20
1210 (2225)	3.20±0.30	2.50±0.20	0.85±0.10	Т	0.75±0.25
1210 (3225)	3.20±0.30	2.50±0.20	2.00±0.20	К	0.75±0.25



Approval Sheet

* Reflow soldering process only is recommended.

6. GENERAL ELECTRICAL DATA

Dielectric	X7R	X5R				
Size	0402, 0603, 08	05, 1206, 1210				
Capacitance range*	1µF to 10µF	0.22µF to 22µF				
Capacitance tolerance**	K (±10%), M (±20%)					
Rated voltage (WVDC)	10V, 16V, 25V, 50V, 100V	6.3V, 10V, 16V, 25V				
Operating temperature	-55 to +125°C	-55 to +85℃				
Capacitance characteristic	11 11 11 11 11 11 11 11 11 11 11 11 11	5%				
Termination	Ni/Sn (lead-free termination)					

* Measured at 1.0±0.2Vrms, 1.0kHz±10%, 30~70% related humidity, 25℃ ambient temperature for X7R, X5R.

** Preconditioning for Class II MLCC: Perform a heat treatment at 150±10°C for 1 hour, then leave in a mbient condition for 24±2 hours before measurement.



ASC_Low Profile_(TT)

7. CAPACITANCE RANGE

7-1 X7R dielectric

	Dielectric	X7R											
	Size		80	305			12	06			1210		
Rated voltage (VDC)		10	16	25	50	10	16	25	50	10	16	100	
	1.0µF (105)							Т					
a	1.5µF (155)												
Capacitance	2.2µF (225)		Т	Т					Т			K	
ita	3.3µF (335)												
Dac	4.7µF (475)	Т						Т					
Cap	6.8µF (685)												
	10µF (106)					Т							
	22µF (226)												

7-2 X5R dielectric

	Dielectric		X5R															
	Size		0402		06	03		08	05				1206				1210	
Rate	ed voltage (VDC)	6.3	10	25	10	16	6.3	10	16	25	6.3	10	16	25	50	10	16	25
	0.22uF (224)			L	Н	Н												
	0.47uF (474)	L		L														
	1.0µF (105)	L			Н	Н		Т	Т	Т		Т	Т	Т	Т			
e	1.5µF (155)							Т	Т			Т	Т	Т				
ano	2.2µF (225)	L					T	T	T	Т		Т	Т	Т	Т			
cit	3.3µF (335)						1 × 7	3	信	Ŧ		Т	Т	Т		Т		
Capacitance	4.7µF (475)	L			Н	135		Ť	$\neg \tau \mathcal{R}$	2 F		Т	Т	Т		Т		
ü	6.8µF (685)				1	THE	"LH	昭不	$2 \times$	S.	-11							
	10µF (106)				K	≤ 1	、イメ	117-1-	210		J	J/T		Т		Т		Т
	22uF (226)				1. T.V.m	TIN T	Ť	Т		22	I.	X	Т				Т	
	47uF (476)				THE					N	∕ דל	12						

8. PACKAGING STYLE AND QUANTITY

Size	Thickness Max (mm)/	Symbol	7" re	el
JIZE		Symbol	Paper tape	Plastic tape
0402 (1005)	0.33		51 15k	-
0603 (1608)	0.60	US/NOHOGY CI	RDORALUM 4k	-
0805 (2012)	0.95	Purci	4k	-
4000 (0040)	0.95	Т	4k	-
1206 (3216)	1.30	J	-	3k
1010 (2005)	0.95	Т	-	3k
1210 (3225)	2.00	К	-	1k

Unit: pieces





9. RELIABILITY TEST CONDITIONS AND REQUIREMENTS

No.	ltem	Test C	Condition		Requirements				
1.	Visual and Mechanical				* No remarkable defect. * Dimensions to conform to individual specification sheet.				
2.	Capacitance	* Test temp.: Room Temperat	ure.		* Shall not exceed the limits given in the detailed spec.				
	Q/ D.F. (Dissipation Factor)	Cap≤10µF, 1.0±0.2Vrms, 1kH Cap>10µF, 0.5±0.2Vrms, 120 ** Test condition: 0.5±0.2Vrm TT18X≧475(10V), TT15X so *Before initial measurement (at 150℃ for 1hr then set for 2)Hz±20%** s,1KHz±10% eries Class II only): To ap	.,	Rated vol. D.F. 100V ≤5% 50V, 25V, 16V, 10V ≤10% 6.3V ≤15%				
4.	Dielectric Strength	* To apply voltage: 250% rate * Duration: 1 to 5 sec.	0		* No evidence of damage or flash over during test.				
5.	Insulation Resistance	* Charge and discharge curre * Test temp.: Room Temperat * To apply rated voltage for m	ure.		≥10GΩ or I	RxC≥100Ω-F whichever is smaller.			
6.	Temperature	With no electrical load.							
ν.	Coefficient	T.C. Operating Tem			T.C.	Capacitance Change			
	Cochiorent	X7R -55~125℃ at 2 X5R -55~85℃ at 25			X7R	Within ±15%			
7.	Adhesive	X5R -55~85℃ at 25 *Before initial measurement (To apply de-aging at 150℃ fc room temp. * Measurement voltage for Cl 1005 Cap≤0.01µF: 0.5∨ Cap>0.01µF: 0.2∨ *0201X104/6.3V~25∨: 0.5∨ 0201X224&474/10∨: 0.5∨ 0402 Cap<1µF: 1∨	Class II only): or 1hr then set for 24 ass II: 0201 Cap<0.1µF:1V 0.1µF≤Cap<1µF: 0.1V *0201S104/6.3V~16 0201S224/6.3V.0 0201X105/6.3V&10 0603 Cap<1µF: 1V 1µF≤Cap≤4.7µF: 0.2V Cap>4.7µF: 0.2V 1206/1210 Cap>10µF: 0.2V 10µF <cap≤100µf: 0.2v<br="">1206X107-6.3V: 0.2</cap≤100µf:>	2V* 3V 3V 3V 3V 3V 3V 3V 3V 3V 3V		within ±15% Kable damage or removal of the terminations.			
	Strength of Termination	* Test time: 10±1 sec.	,	,	No rema				
8.	Vibration Resistance	 * Vibration frequency: 10~55 Hz/min. * Total amplitude: 1.5mm * Test time: 6 hrs. (Two hrs each in three mutually perpendicular directions.) * Before initial measurement (Class II only): To apply de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. * Cap./DF(Q) Measurement to be made after de-aging at 150°C for 1hr then set for 24±2 hrs at room temp. 				kable damage. nge and Q/D.F.: To meet initial spec.			
9.	Solderability	* Solder temperature: 235±5° * Dipping time: 2±0.5 sec.			95% min. c	coverage of all metalized area.			
10.	Bending Test	 * The middle part of substrate of the pressurizing rod at a ra the deflection becomes 1 mm maintained for 5±1 sec. * Before initial measurement To apply de-aging at 150°C for room temp. * Measurement to be made a 24±2 hrs. 	te of about 1 mm per and then the press (Class II only): or 1hr then set for 24	er second until sure shall be 1±2 hrs at	* Cap char X7R/X5R (This capa	kable damage. Ige : : within ±12.5% acitance change means the change of capacitance unde exure of substrate from the capacitance measured before			

ASC_Low Profile_(TT)

Copyright © by Walsin Technology Corporation. | All rights reserved.



Approval Sheet

Multilayer Ceramic Capacitors	amic Capacitors
-------------------------------	-----------------

Resistance to Soldering Heat * Dipping time: 10±1 sec * Preheating: 120 to 150°C for 1 mir capacitor in a eutectic solder. *Before initial measurement (Class at 150°C for 1hr then set for 24±2 h *Cap. / DF(Q) / I.R. Measurement to	II only): To apply de-aging s at room temp.
150℃ for 1hr then set for 24±2 hrs	at room temp.

* "Room condition" Temperature: 15 to 35°C, Relative humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.



ASC_Low Profile_(TT)



No.	ltem	Test Condition	Requirements			
12.	Temperature Cycle	* Conduct the five cycles according to the temperatures an time.	d * No remarkable damage. * Cap change :			
		Step Temp. (°C) Time (min.) 1 Min. operating temp. +0/-3 30±3 2 Room temp. 2-3 3 Max. operating temp. +3/-0 30±3 4 Room temp. 2-3 * Before initial measurement (Class II only): To apply de-age at 150°C for 1hr then set for 24±2 hrs at room temp. * * Cap. / DF(Q) / I.R. Measurement to be made after de-agi at 150°C for 1hr then set for 24±2 hrs at room temp. *	X7R/X5R: within ±7.5% * Q/D.F., I.R. and dielectric strength: To meet initial requirements.			
13.	Humidity (Damp Heat) Steady State	 * Test temp.: 40±2°C * Humidity: 90~95% RH * Test time: 500+24/-0hrs. * Before initial measurement (Class II only): To apply de-ag at 150°C for 1hr then set for 24±2 hrs at room temp. * Cap. / DF(Q) / I.R. Measurement to be made after de-agi at 150°C for 1hr then set for 24±2 hrs at room temp. 	100V ≤7.5%			
14.	Humidity (Damp Heat) Load	 * Test temp.: 40±2°C * Humidity: 90~95%RH * Test time: 500+24/-0 hrs. * To apply voltage : Rated voltage. * Before initial measurement (Class II only): To apply de-agat 150°C for 1hr then set for 24±2 hrs at room temp . * Cap. / DF(Q) / I.R. Measurement to be made after de-agat 150°C for 1hr then set for 24±2 hrs at room temp . 	25V, 16V ≤15%			
15.	High Temperature Load (Endurance)	Test temp. : PASSIVE SYSTEM X7R: 125±3°C X5R: 85±3°C * Test time: 1000+24/-0 hrs: * * To apply voltage: 150% of rated voltage. * **100% of rated voltage for below range. * Size Dielectric Rated voltage TT15 X5R 6.3V (C≥1.0µF TT21 X5R/X7R/X6S ≤ 10V C≥10µF *Before initial measurement (Class II only): To apply de-ag at 150°C for 1hr then set for 24±2 hrs at room temp. * Cap. / DF(Q) / I.R. Measurement to ©r de-aging at 150°C 1hr then set for 24±2 hrs at room temp. *	No remarkable damage. *Cap change: X7R/X5R: within ±25%Q/D.F. value: X7R/X5R:Rated vol.D.F.100V≤7.5%25V, 16V≤15%10V≤20%50V, 6.3V≤30%*I.R.: 1GΩ or RxC≥10 Ω-F whichever is smaller.			

* "Room condition" Temperature: 15 to 35°C, Relative humidity: 25 to 75%, Atmospheric pressure: 86 to 106kPa.

ASC_Low Profile_(TT)

APPENDIXES

■ Tape & reel dimensions





Size	0402	0603	0805	12	206	12	10
Thickness	L	н	Т	Т	J	Т	К
A	0.70 +/-0.20	1.05 +/-0.30	1.50 +/-0.20	1.90 +/-0.50	< 2.00	< 3.05	< 3.05
B ₀	1.20 +/-0.20	1.80 +/-0.30	2.30 +/-0.20	3.50 +/-0.50	< 3.70	< 3.80	< 3.80
Т	≦0.80	≦1.20	≦1.20	≦1.20	0.23 +/-0.1	0.23 +/-0.1	0.23 +/-0.1
Ko	-		- -		< 2.00	< 1.50	< 2.50
w	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00+/-0.30	8.00 +/-0.30	8.00 +/-0.30	8.00 +/-0.30
Po	4.00 +/-0.10	4.00 +/-0.10	PASS 4.00 SYSTEM +/-0.10	ALLI4.00 = +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10
10xP₀	40.00 +/-0.10	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20	40.00 +/-0.20
P ₁	2.00 +/-0.05	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10	4.00 +/-0.10
P ₂	2.00 +/-0.05	2.00 +/-0.05	2.00	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05	2.00 +/-0.05
Do	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0 GV ()	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0	1.50 +0.1/-0
D ₁	-	-	-	-	1.00 +/-0.10	1.00 +/-0.10	1.00 +/-0.10
E	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10	1.75 +/-0.10
F	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05	3.50 +/-0.05



Size	0402, 0603, 0805, 1206, 1210						
Reel size	7"	10"	13"				
С	13.0±0.5	13.0±0.5	13.0±0.5				
W 1	10.0±1.5	10.0±1.5	10.0±1.5				
Α	178.0±2.0	250.0±2.0	330.0±2.0				
N	60.0+1.0/-0	50 min	50 min				

Page 8 of 10



Example of customer label





*Customized label is available upon request

- j. Order bar code including series and item numbers
- k. Serial number of label

Constructions

No.	Name		X7R, X5R		
1	Ceramic material		BaTiO ₃ based		
2	Inner electrode		· ME LA X		5
3		Inner layer	Cu	¢T.J	
4	Termination	Middle layer	Ni	7 Zr	
5		Outer layer	Sn (Matt)		Fig. 5 The construction of MLCC
PASSIVE SYSTEM ALLIANCE					

Storage and handling conditions

- (1) To store products at 5 to 40°C ambient temperature and 20 to 70%. related humidity conditions; MSL Level 1.
- (2) The product is recommended to be used within one year after shipment. Check solderability in case of shelf life extension is needed.

Cautions:

- a. The corrosive gas reacts on the terminal electrodes of capacitors, and results in the poor solderability. Do not store the capacitors in the ambience of corrosive gas (e.g., hydrogen sulfide, sulfur dioxide, chlorine, ammonia gas etc.)
- b. In corrosive atmosphere, solderability might be degraded, and silver migration might occur to cause low reliability.
- c. Due to the dewing by rapid humidity change, or the photochemical change of the terminal electrode by direct sunlight, the solderability and electrical performance may deteriorate. Do not store capacitors under direct sunlight or dewing condition. To store products on the shelf and avoid exposure to moisture.



Recommended soldering conditions

The lead-free termination MLCCs are not only to be used on SMT against lead-free solder paste, but also suitable against lead-containing solder paste. If the optimized solder joint is requested, increasing soldering time, temperature and concentration of N_2 within oven are recommended.



Fig. 6 Recommended reflow soldering profile for SMT process with SnAgCu series solder paste.



Fig. 7 Recommended wave soldering profile for SMT process with $\ensuremath{\mathsf{SnAgCu}}$ series solder.



ASC_ Low Profile_(TT)